

Abstract

5 **TESTING APPARATUS AND METHOD FOR TESTING THE CONTACTING
BETWEEN A SEMICONDUCTOR DEVICE AND A CARRIER**

10 The invention relates to a testing apparatus, a testing system and a testing method, in particular for testing the contacting between a semiconductor device and a carrier.

15 The invention includes loading of a carrier with a semiconductor device, such that the contacting between the carrier and the semiconductor device is tested immediately after the loading of the carrier with the semiconductor device.